



# Wideband Very-Near-Field Array of Probes for Efficient EMI Measurements

## **EMSCAN EMxpert ERX+**



## Very-near-field magnetic measurements expert since 1989

Unique patented products for RF/MW and EMC/EMI

- Far-field = pattern is not changing with the distance
- Near-field = anything not in the far-field
- Stay out of the reactive region? **Not EMSCAN!**
  - Very-near-field

Radiating Near Field

$$\lambda/2\pi \leq d < 2D^2/\lambda$$

or

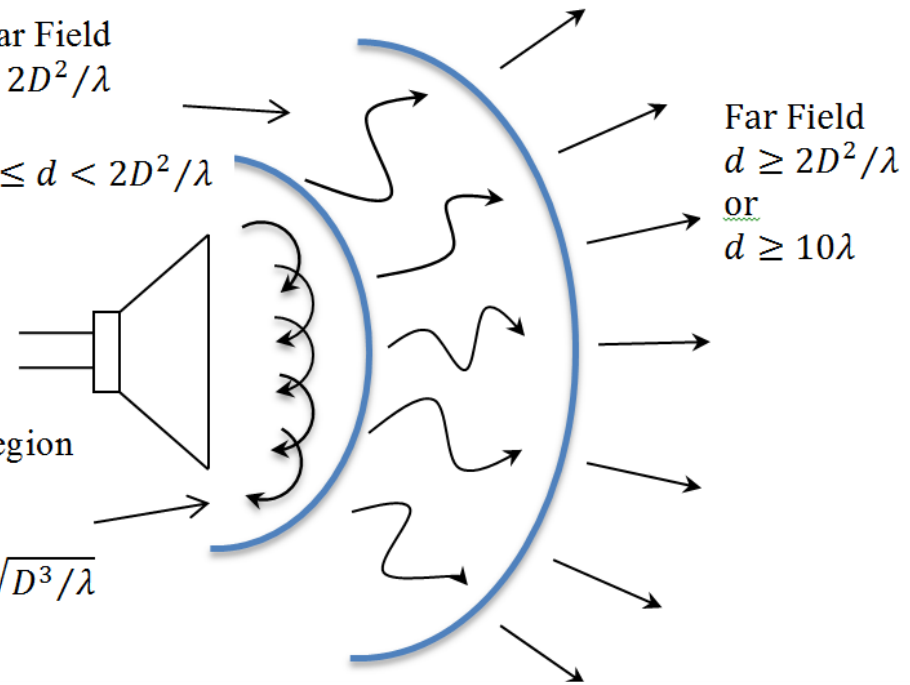
$$0.62 \sqrt{D^3/\lambda} \leq d < 2D^2/\lambda$$

Reactive Region

$$d < \lambda/2\pi$$

Or

$$d < 0.62 \sqrt{D^3/\lambda}$$



# Introduction

World Leading Developer of Visual **Real-Time**  
EM and RF **Pre-Compliance** Test Solutions

Antenna and PCB **Designers**

Product Integration and Verification **Engineers**

**Diagnostic Tool**

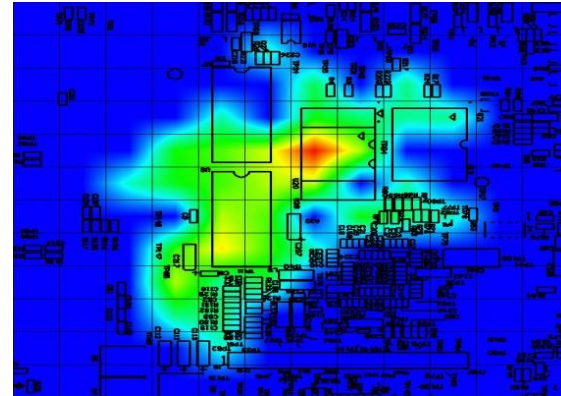
**Manufacturing Quality Control**



# Chamber on your Desktop

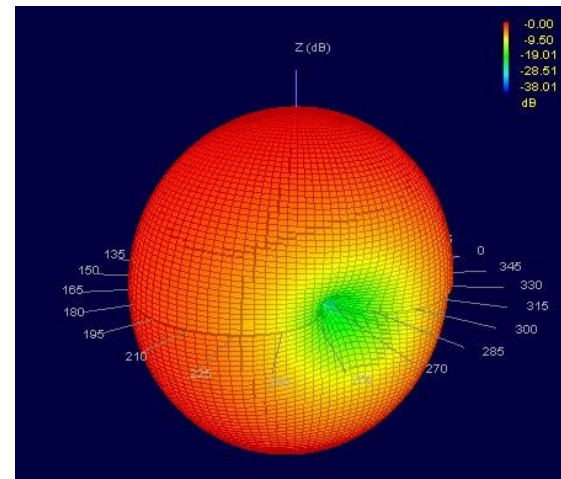
## ● EMxpert

- EMC diagnostic tool to rapidly diagnose and solve EMC/EMI problems with real-time PCB emission analysis



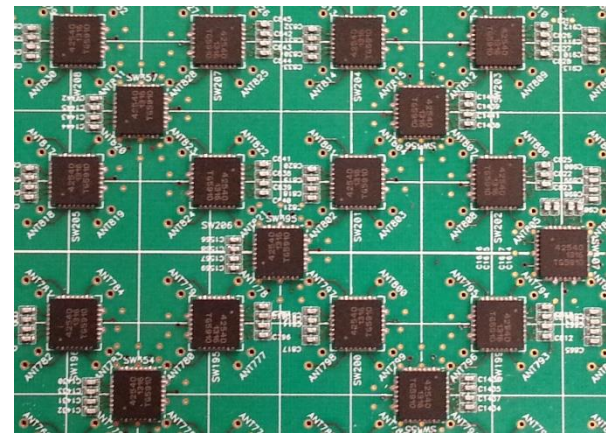
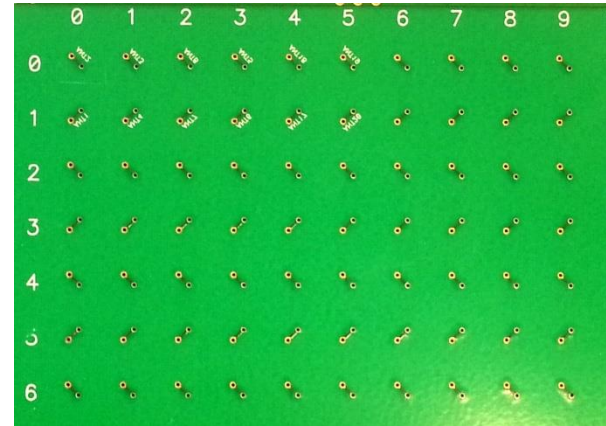
## ● RFXpert

- APM tool enabling to quickly evaluate performance and optimize designs with real-time antenna performance characterization



# Fundamentals

- High-density planar antenna array
- High-speed electronic switching
- Very-near-field measurements
- Far-field predictions
- “Real-time” real-fast
- No chamber

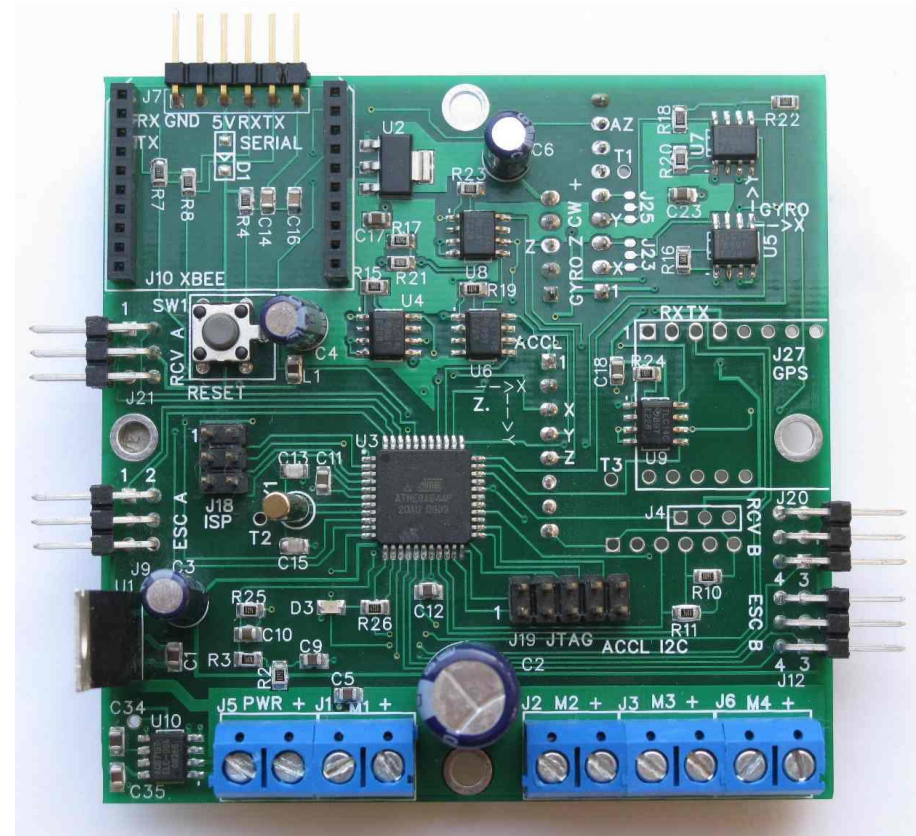




**EM**xpert

**Overview**

# PCB and IC Radiated EMC/EMI Issues



# EMxpert Family



EHX



EHX+



ERX+



# Functionality

- **Spectral scan**

- Problem frequencies
- Frequency: 150 kHz to 8 GHz

- **Very-near-field spatial scan**

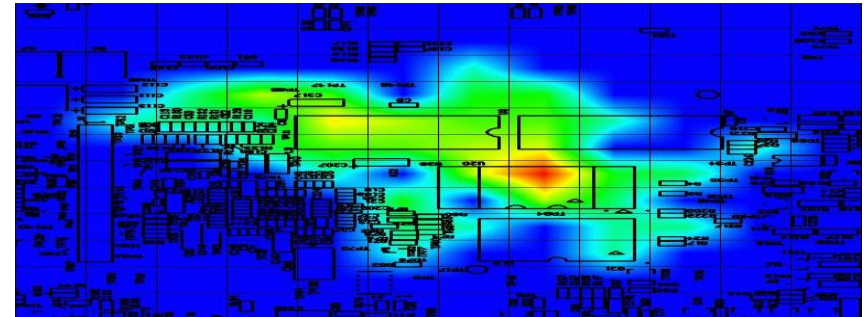
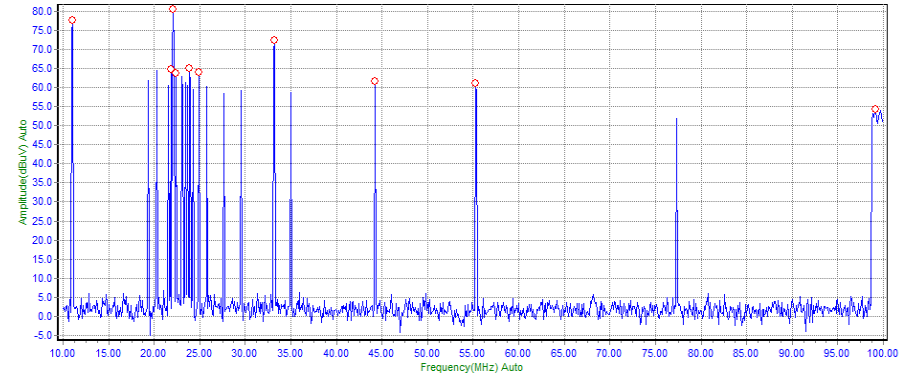
- Sources of radiated emissions
- Hx and Hy
- Resolution: 3.75 mm to 0.1 mm

- **Far-Field prediction for PCB**

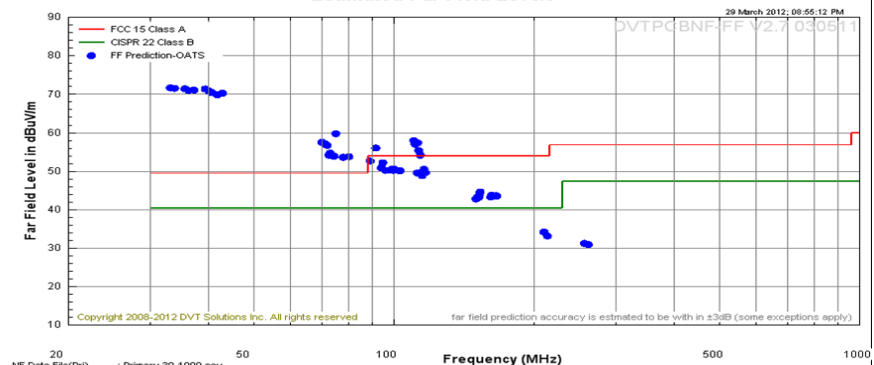
- Regulatory data

- **Compare and overlay functions**

- **Automated report generator**



PCB Modem Test Case 1  
Estimated Far Field Levels

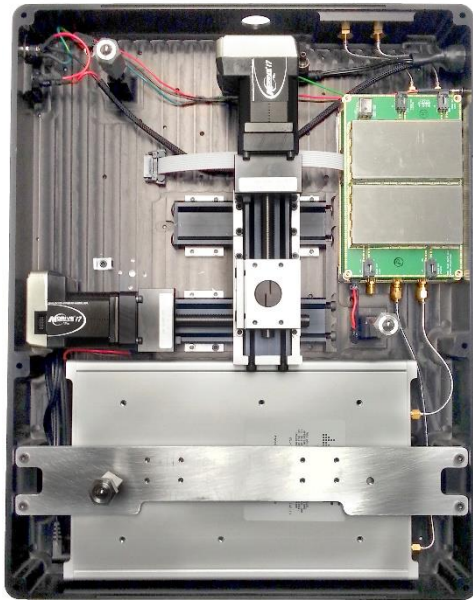




**EM**xpert

# ERX+ Technical Specifications

# Hardware

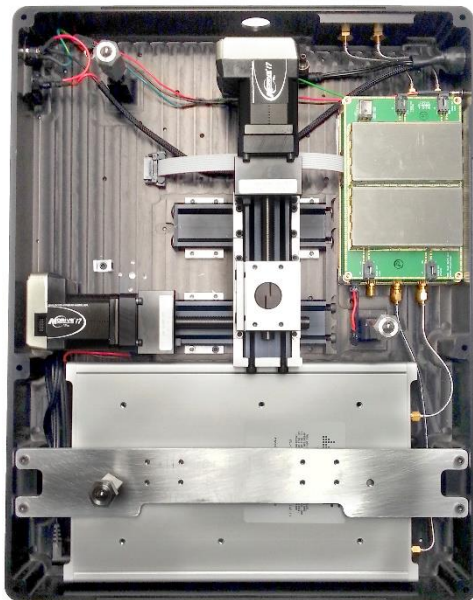


# Concept

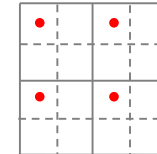
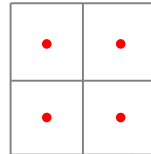
- **Scanner moves along X and Y axis**
  - Steps defined by required resolution
- **Multiple electronic scans per mechanical step**
  - Rich data acquisition
- **Maximum number of mechanical steps: 16384**
  - Regardless of DUT size
- **Maximum travelled distance: 7.5 mm**
  - Regardless of DUT size

# Higher Resolution Spatial Scan

- Move the entire probe array to synthesize small probe spacing

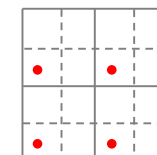
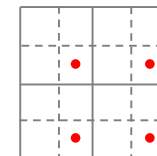
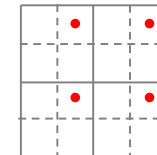
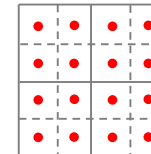


Level 1



=

Level 2



# Specifications

- **8 measurement levels - 0**

ERX Control Level

Level 1 --- 7.50 mm	▼
Level 1 --- 7.50 mm	
Level 2 --- 3.75 mm	
Level 3 --- 1.88 mm	
Level 4 --- 0.94 mm	
Level 5 --- 0.47 mm	
Level 6 --- 0.24 mm	
Level 7 --- 0.12 mm	
Level 8 --- 0.06 mm	

- **Interleaved scan i.e. blind spot reduction**

- 2 x duration

Interleaved Scan

ERX Control Level

Level 1 --- 7.50 mm ▼

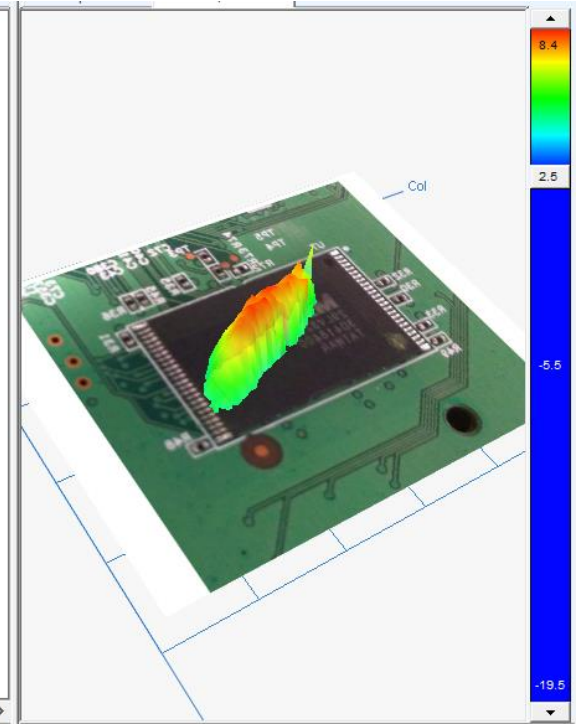
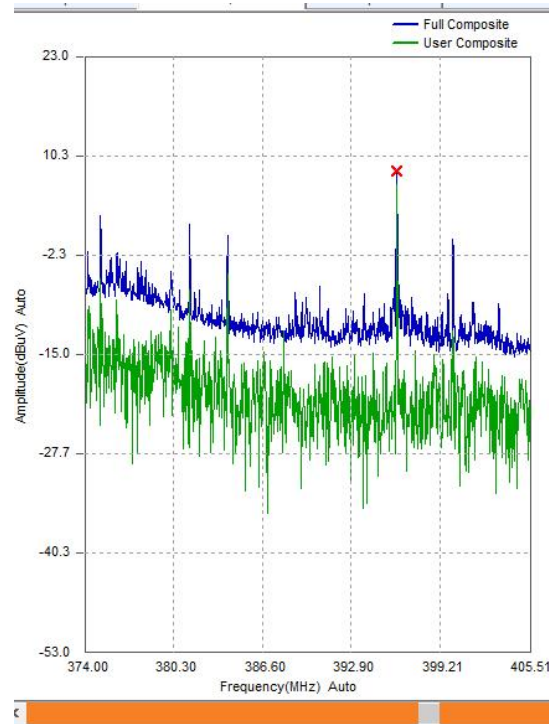


# Frequency Domain Data

**Currently Available**

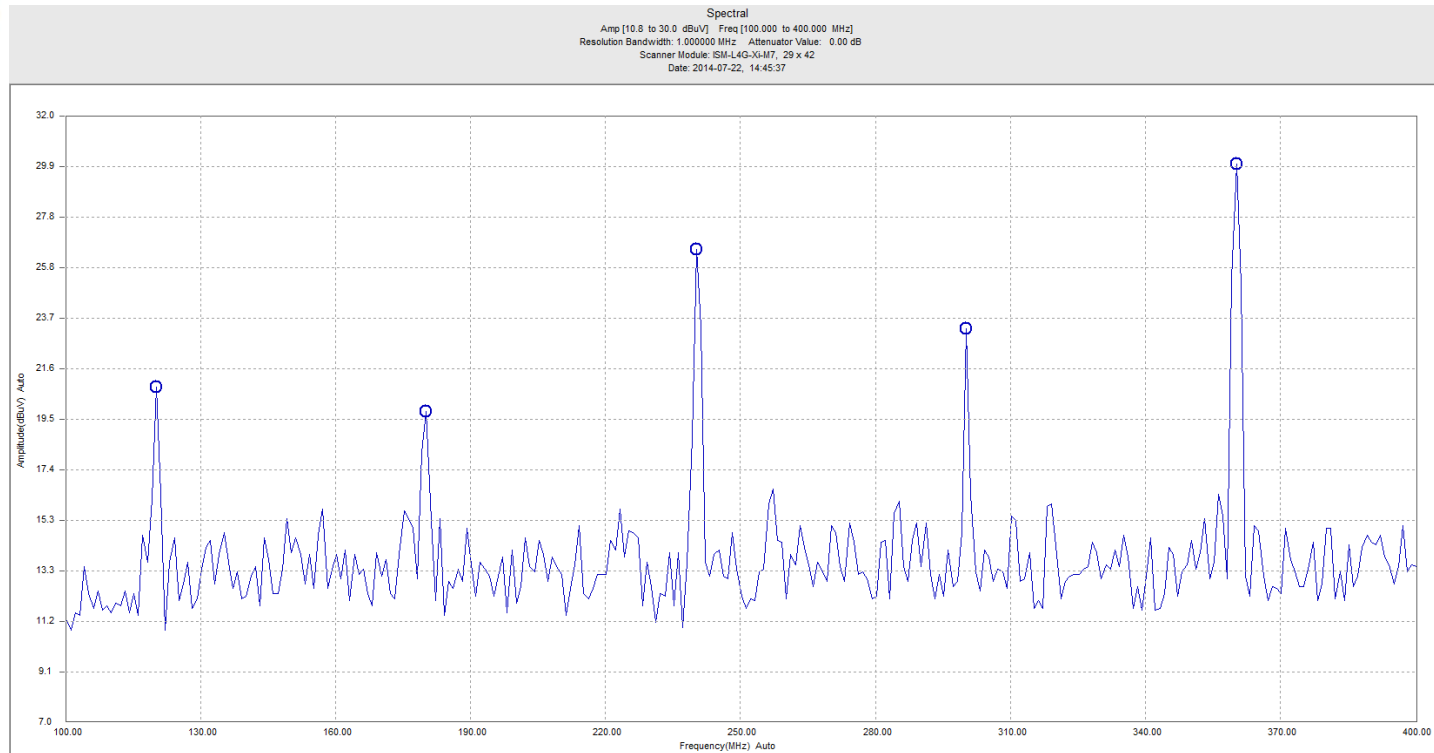
# Current Spectral Domain Data

- Probes measured sequentially
- Spectral content at each probe is available
- Spatial distribution for every frequency is available

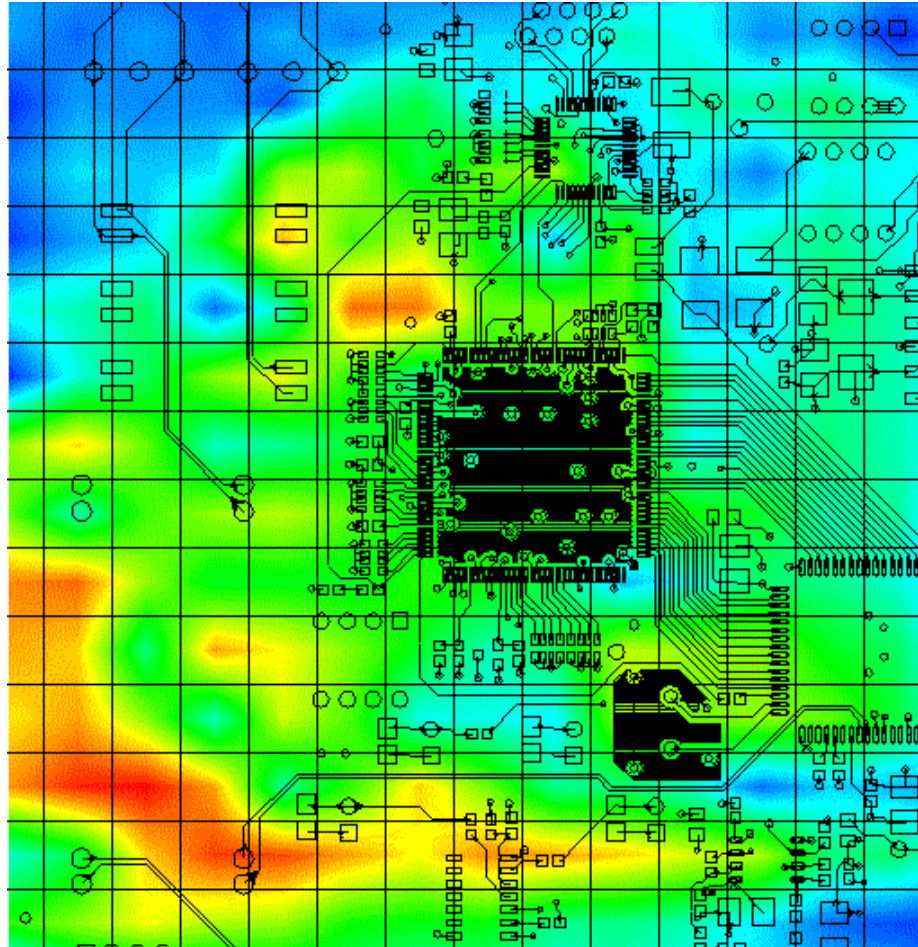




# L1 Spectral Scan

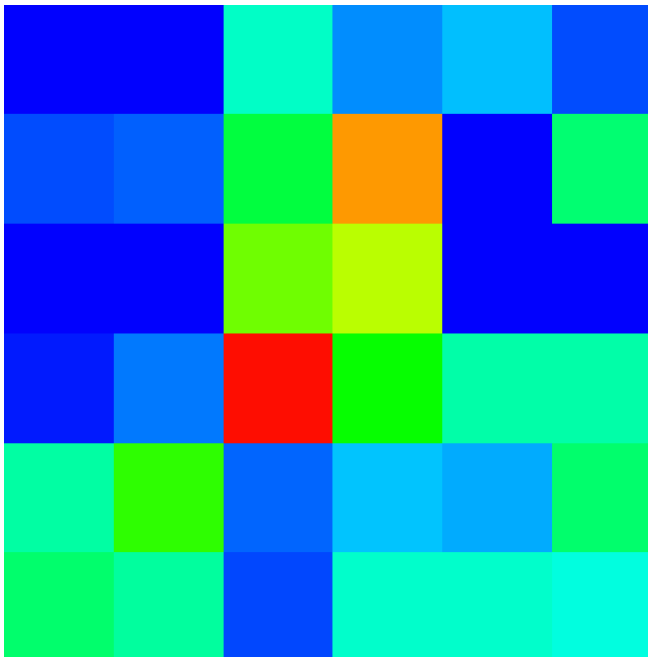


# L1 Spatial Scan: “Real-Time” Scanning

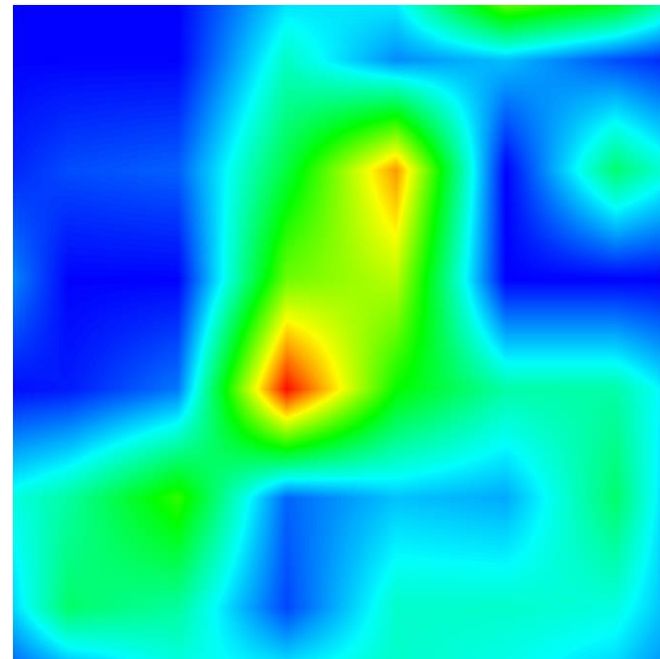


# L1 Spatial Scan: Standard Resolution

Physical 7.5 mm No Interpolation

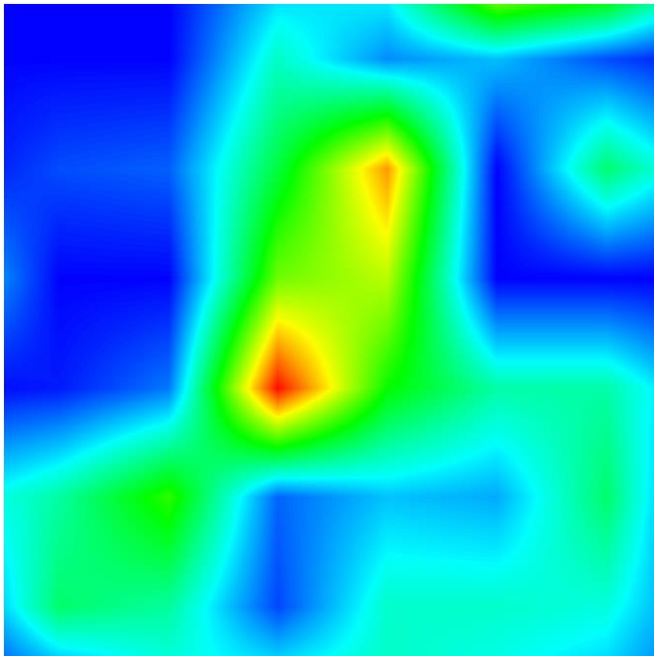


Effective 3.75 mm Interpolation

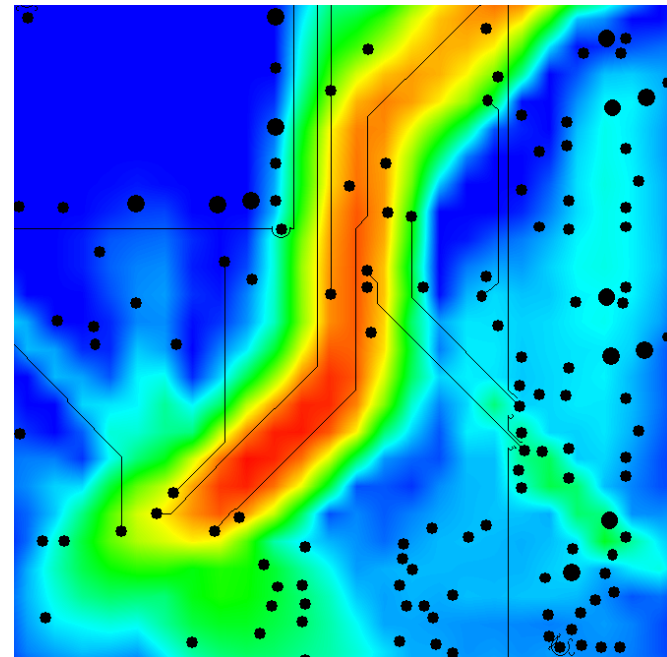


# L2 – L8 High Resolution Spatial Scan

Level 1

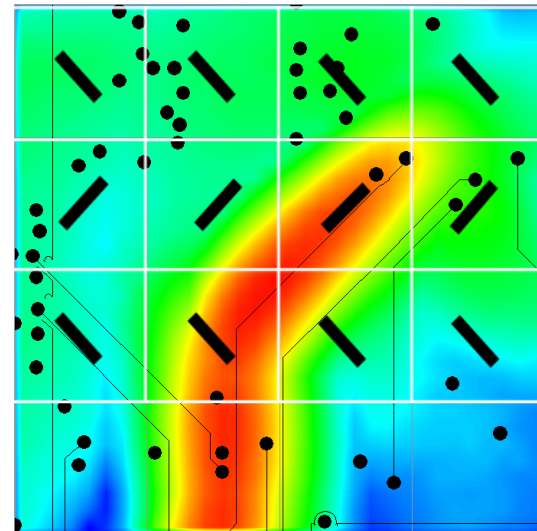
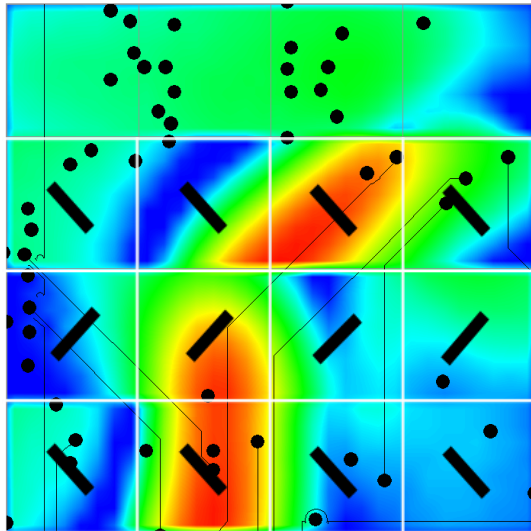


Level 3

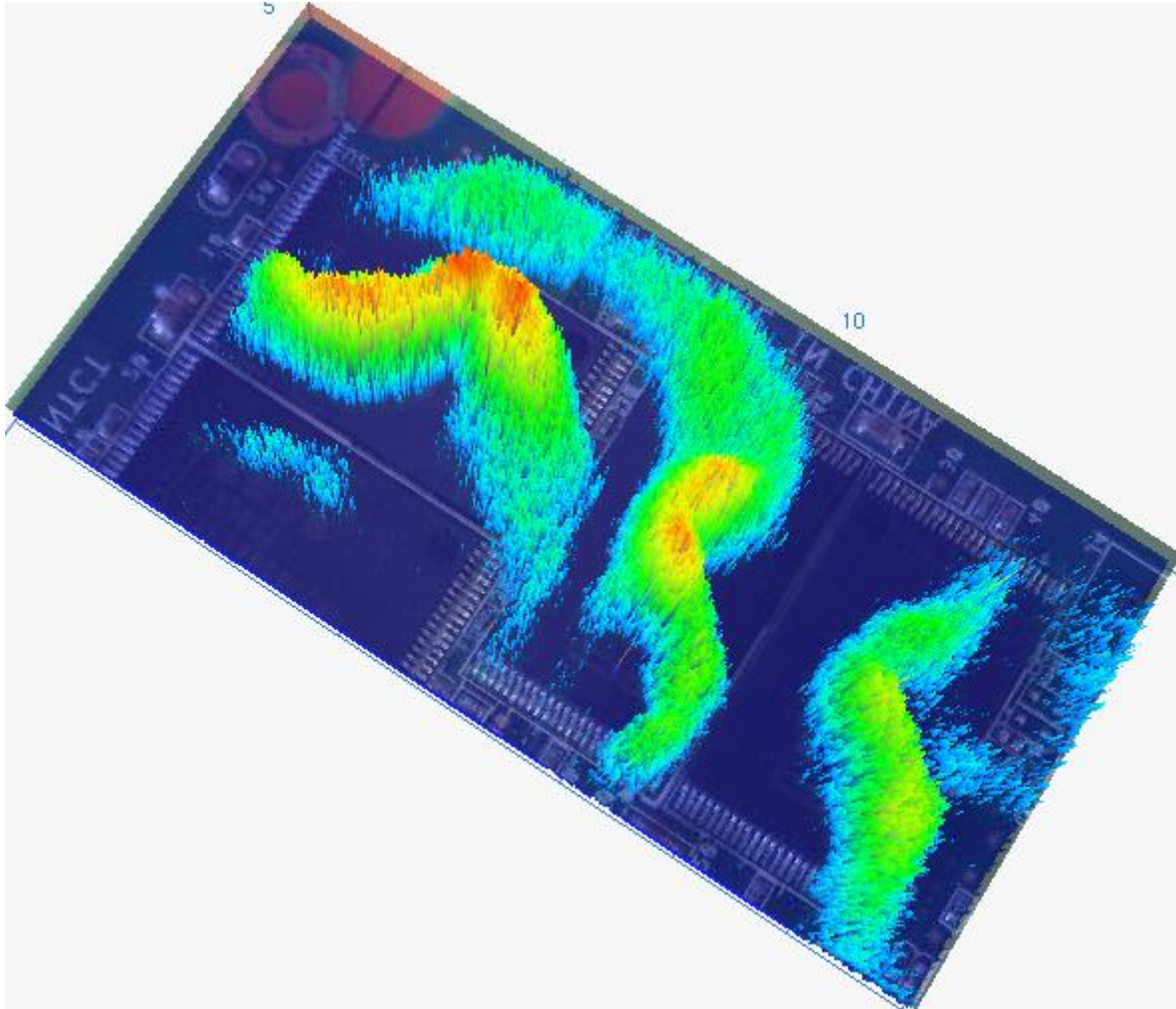


# L1-L8 Spatial Scan: Interleaved

- **Powerful feature to remove blind spot**
  - First original scan
  - Second scan with probes shifted one row



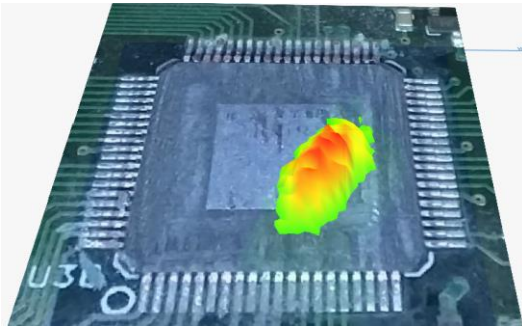
# L8 Spatial Scan: 3D Interleaved



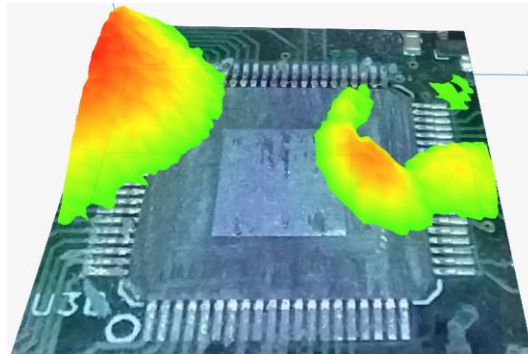
# IC Analysis

- About 2 minutes per scan

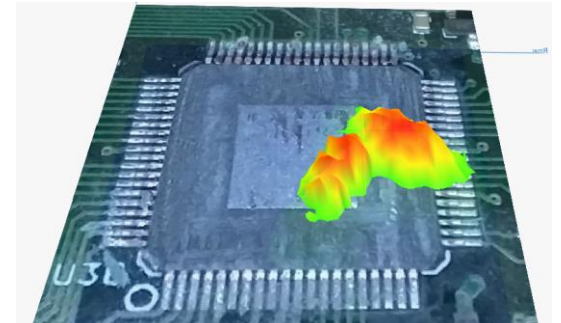
100 MHz



120MHz

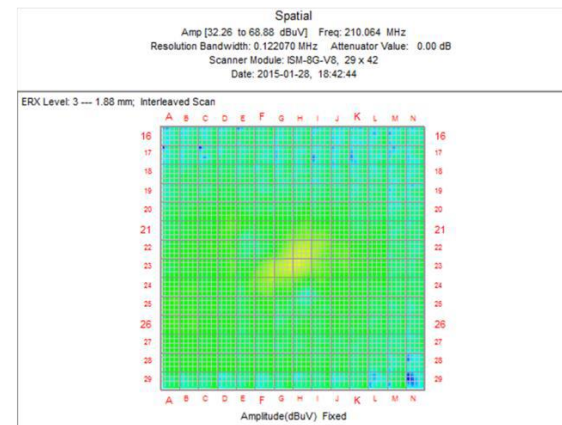
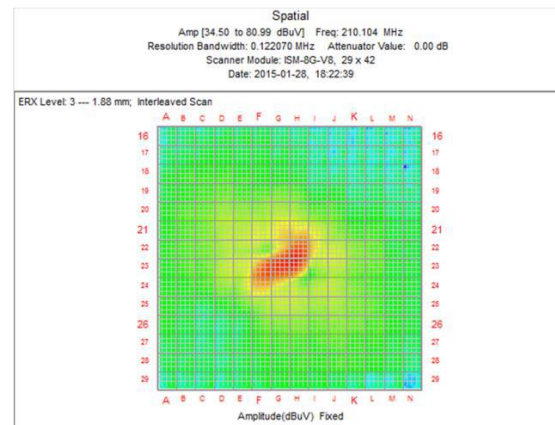
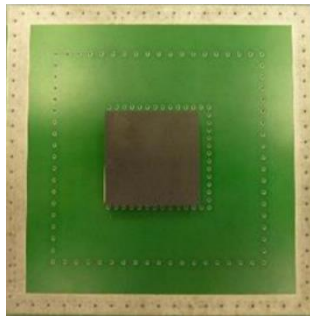


130MHz



# IC Analysis

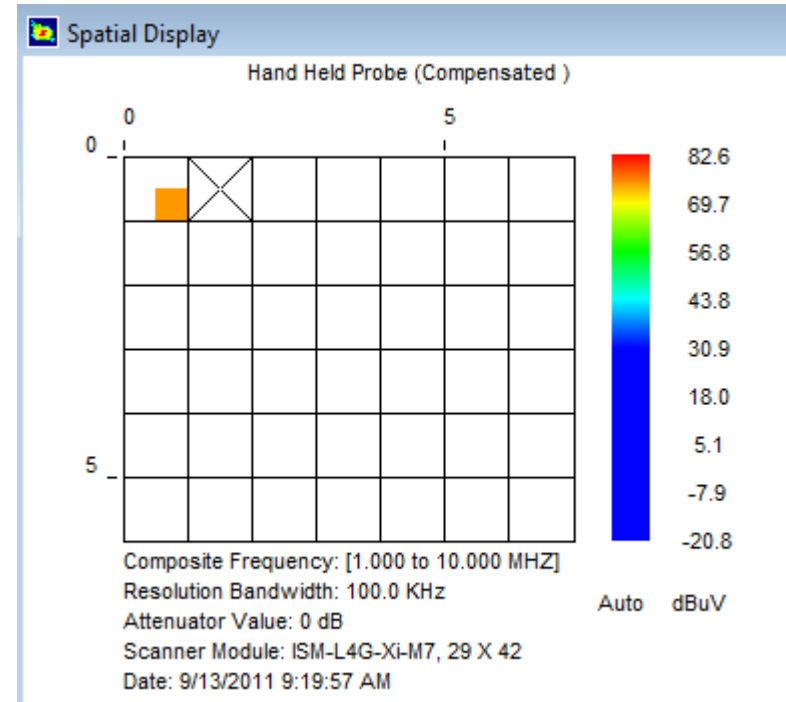
## ● Effectiveness of Shielding





# Spectral/Spatial Scan: Hand-Held Probe

- External probe
  - E-field probe
  - Hz probe
- Programmed mode up to 19,955,712 measurements



# By-Pass

- **Directly from scanner to analyzer externally**
  - Better amplifier at a specific frequency
  - Greater than 20 dB attenuator
  - Passband filter

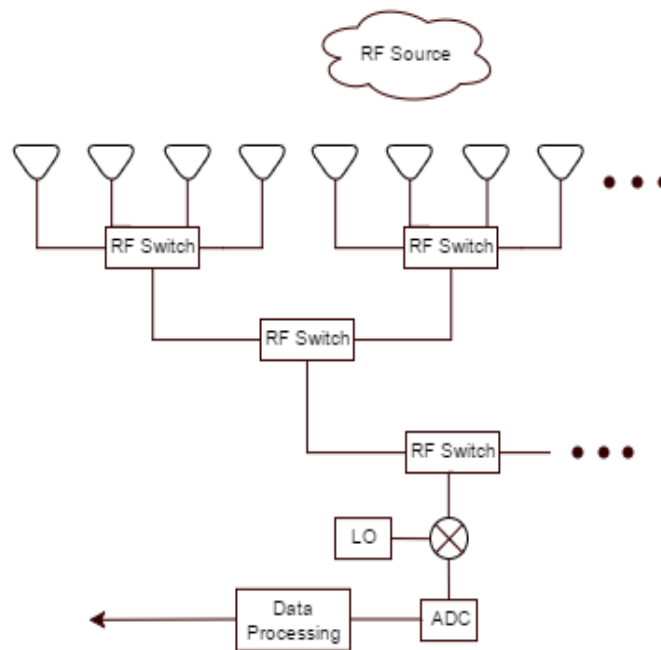




# Synchronous Time Domain Data

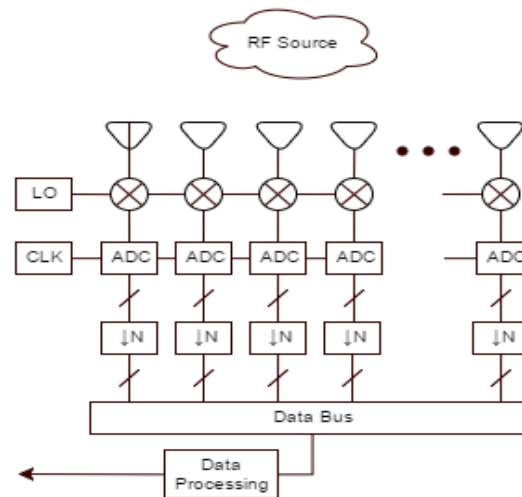
## New Technology in 2018

# Existing Architecture



# New Architecture

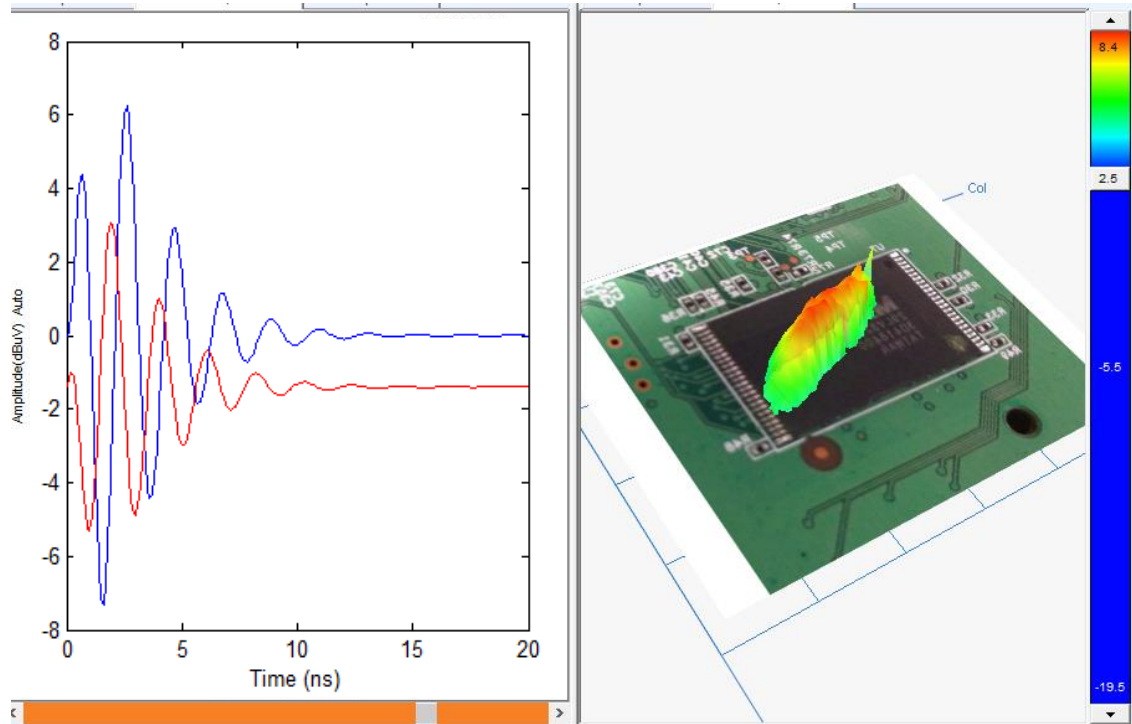
- Under development for 2018 up to 20 GHz



Synchronous data capture  
Single event capture possible

# Time Domain Functionality

- Many probes measured simultaneously
- Time domain content available at each probe
- Spatial distribution of energy available at every point in time



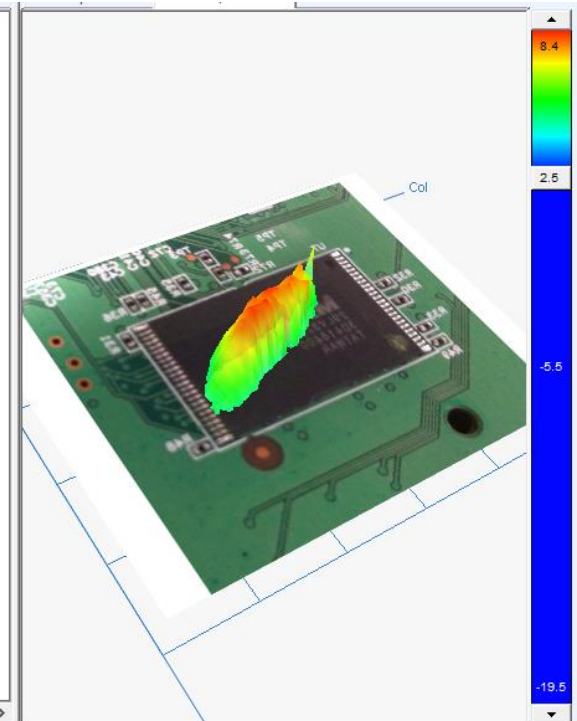
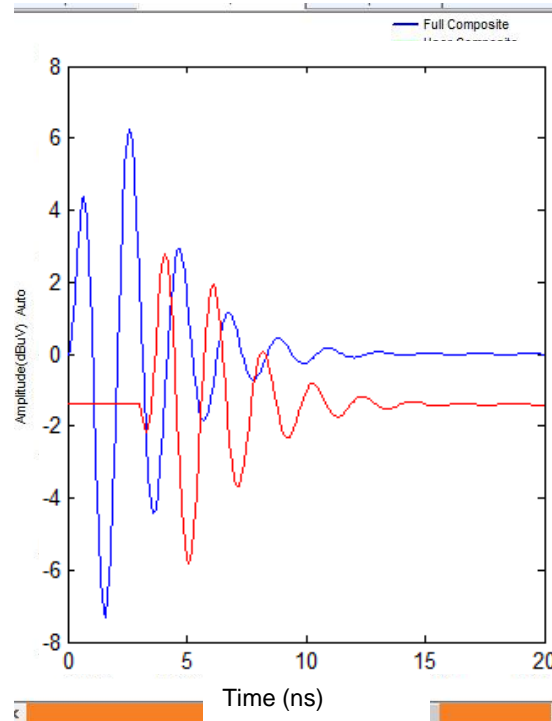


# **Asynchronous Time Domain Data**

## **On-Demand Development Feasible in 2017**

# Easily Obtainable Time Domain Data

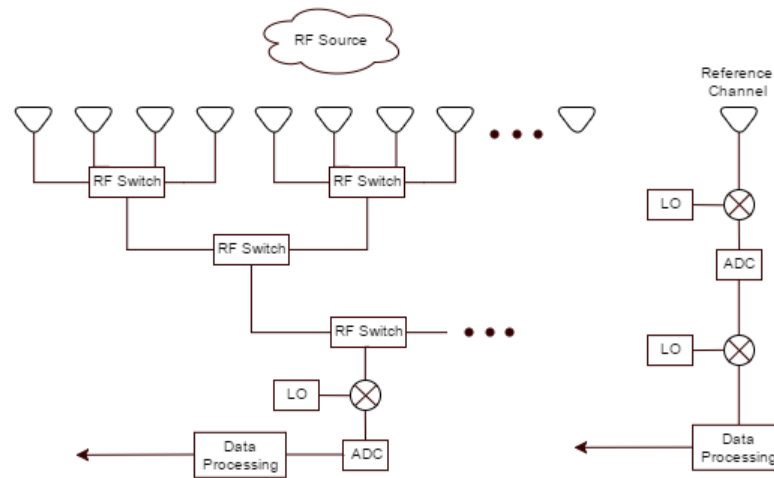
- Probes measured sequentially
- Time domain content at each probe is available
- Content from each probe is not synchronized





# Architecture Changes

- Similar to RFXpert implementation



Asynchronous with external reference  
May require cyclostationary process

# Business Case

- **Displacing existing plans and commitments**
  - Four ERX+ cover development and opportunity costs
  - Aggregated from multiple customers